

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/710,331	BONALLE ET AL.		
Examiner	Art Unit		

2876

Daniel I. Walsh

	SEAR	CHED	
Class	Subclass	Date	Examiner
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INI	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	D	EXMR		
EAST Search attached	11/14	4/2005	DW	